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Company Profile



Atecom Technology Co., Ltd.

is the manufacturer and supplier of semiconductor materials established at Taipei of Taiwan in 1998.

We manufacture and cooperate with our partners for the various crystals on Semiconductor and Compound materials like Silicon ingots/wafers, Epitaxial wafers, Solar wafers, Sapphire, GaAs, SiC, GaN, InP and Ge wafer for applications to Optoelectronics, MEMS, LED, Power devices, Solar modules and IC's.

In the meantime, we keep expanding our product lines to the field of Sputtering Targets, Aluminium oxide, Germanium tetrachloride (GeCl_4) materials in order to provide more services and choices to our customers.

Business Product lines

Semiconductor

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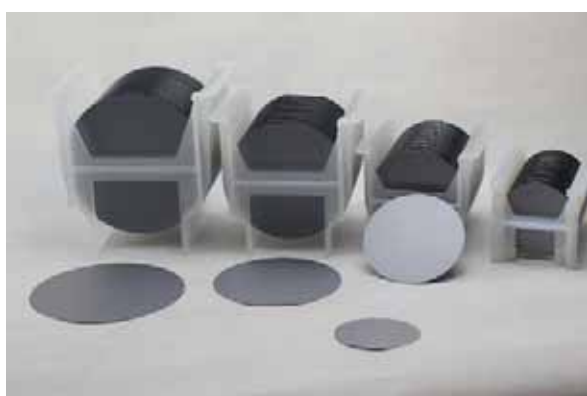
Silicon Monocrystal Ingot

Product Name	Silicon Ingot				Unit
Growth Method	CZ	MCZ	GDFZ	NTD	
Diameter*	50.8 ~ 200				mm
Diameter Tolerance	± 0.5				mm
Crystal Orientation	<111> / <100> / <110>				degree
Type / Dopant	N: Arsenic / Antimony / Phosphorus / Red Phosphorus				
	P: Boron				
Resistivity	0.001 ~ 300	1 ~ 20,000	30 ~ 800		Ω.cm
* Other customized specifications are welcome					



Silicon Wafer

Product Name	Silicon Wafer						Unit
Diameter (mm)	50.8	76.2	100	125	150	200	mm
Growth Method	CZ / MCZ / GDFZ / NTD						
Type / Dopant	N: Arsenic / Antimony / Phosphorus / Red Phosphorus						
	P: Boron						
Resistivity	CZ / MCZ: 0.001 ~ 300						Ω.cm
	GDFZ: 1 ~ 20,000						
	NTD: 30 ~ 800						
Thickness*	381	381	525	525	675	725	μm
Thickness Tolerance*	Typical ± 25						μm
TTV*	≤ 10						μm
Bow*	≤ 25	≤ 30	≤ 30	≤ 30	≤ 30	≤ 40	μm
* Other surface conditions & customized specifications are welcome							
* Backside Seal LTO & Poly both are available							
* Other unmentioned parameters are per Semi Standard							



Epitaxial Wafer

Product Name	Silicon Epitaxial Wafer					
Characteristics	Parameters					Test Method
Dopant	Boron / Phosphorus / Arsenic					
Orientation	<100> / <111>					
Resistivity	Epi Reactor	Diameter	Type	Epi resistivity	Uniformity	ASTM F723 F1392
	Batch	100mm	P/P ⁺⁺ ;	4x10 ⁻³ (B:1x10 ⁻²) ⁻³ Ω.cm	≤ ±6%	
		125mm	N/N ⁺ ;			
		150mm	N/N ⁺⁺ ;	3-30 Ω.cm	≤ ±6%	
		200mm	N/N ⁺ /N ⁺⁺ ;	> 30 Ω.cm	≤ ±6%	
	Single	150mm	N/P/P;	0.3-3 ohm.cm	≤ ±6%	
200mm		P/N/N ⁺	3-30 ohm.cm	≤ ±6%		
Thickness	Epi Reactor	Diameter	Type	Epi thickness	Uniformity	FTIR ASTM F95
	Batch	100mm	P/P ⁺⁺ ;	3-100 μm	≤±6%	
		125mm	N/N ⁺ ;			
		150mm	N/N ⁺⁺ ;			
		200mm	N/N ⁺ /N ⁺⁺ ;			
	Single	150mm	N/P/P;	0.1-20 μm	≤ ±6%	
200mm		P/N/N ⁺				
Stacking Faults	≤ 10 ea/cm ²					ASTM F1810
Slip	≤ 5 lines, total length <1/2 diameter					ASTM F1725 F1726
Surface Condition	Free of Haze, Scratches, Craters, Orange Peel, Cracks, Crow's Feet, Edge Chips, Foreign Matter, Back Surface Contamination					ASTM F523
Edge Crown	Projection above wafer surface not to exceed 1/3 of Epi layer thickness					
Point Defects	SEMI Standard					ASTM F523

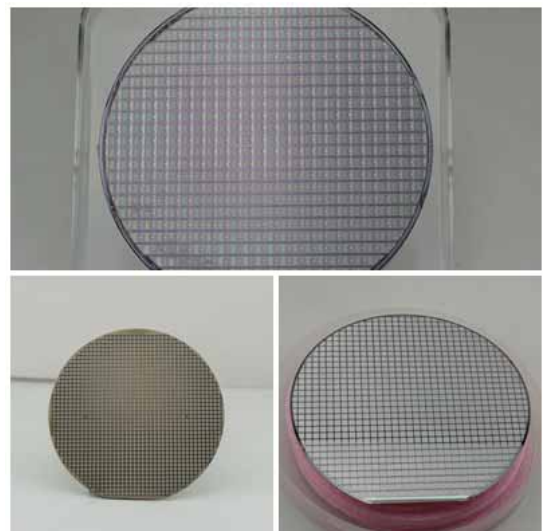
Processing – Schottky Chip/Diode

Product Name	Schottky Barrier Wafer			Unit
Parameter	SB Series	MBR Series	TBR Series	
$V_{RRM (Max)}$	20 ~ 60	35 ~ 100	45 ~ 200	V
$I_F (Max)$	1.0 ~ 5.0	7.0 ~ 16	1.0 ~ 30	A
$V_{FM (Max)}$	0.48 ~ 0.70	0.63 ~ 0.84	0.42 ~ 0.70	V
$I_{RRM (Max)}$ $V_{RM}=V_{RRM}$	0.5	0.1 ~ 1.0	0.1 ~ 1.0	mA
Package	DO-41 / DO-15 / DO-201AD	DO - 220AC	DO-220AB	
* Other customized specifications are welcome				



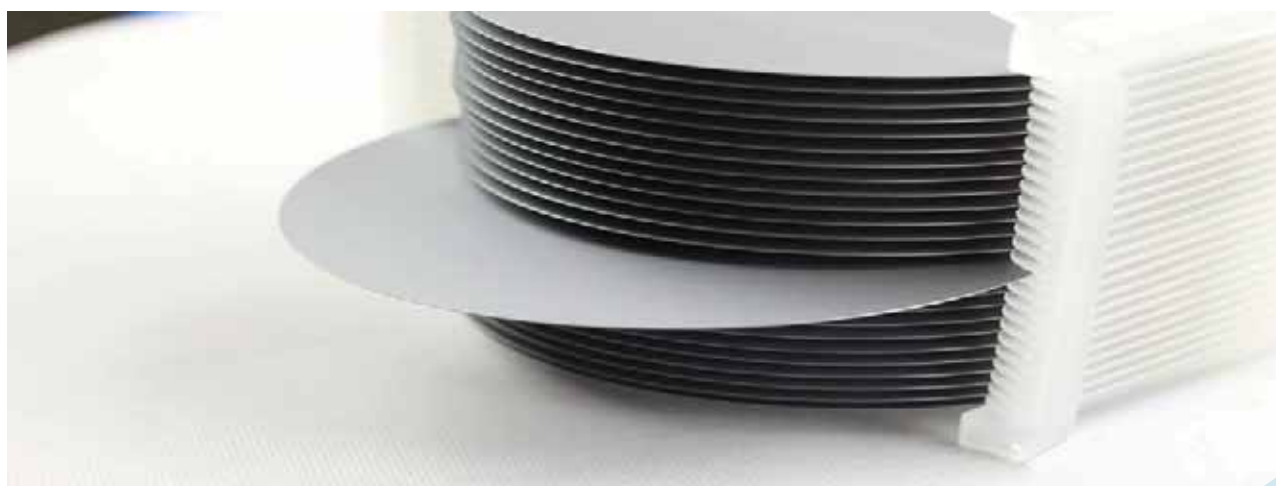
Processing – GPP Chip/Diode

Product Name	GPP Wafer			Unit
Parameter	SG010-15	SG020-60	SG030-250	
Size	40 ~ 60	65 ~ 98	105 ~ 180	mil
I_F	1.0 ~ 1.5	2.0 ~ 6.0	8.0 ~ 25	A
I_{FSM}	15 ~ 55	70 ~ 175	200 ~ 600	A
$I_R (V_R=V_{RRM})$	2.0	2.0	2.0	μA
V_{RRM}	200 ~ 1400			V
Metal	Ni / Au			
Junction Temp.	150			$^{\circ}C$
* Other customized specifications are welcome				



SOI Wafer

Product Name	SOI Wafer				Unit
Diameter	100	125	150	200	mm
Substrate Specification					
Growth Method	CZ / MCZ / FZ				
Orientation	<100> / <111> / <110>				degree
Dopant	P: Boron				
	N: Arsenic / Antimony / Phosphorus/ Red Phosphorus				
Resistivity*	0.001 ~ 20000				Ω .cm
Device Layer					
Thickness*	≥ 1.5	0.1~ 300			μ m
Buried Oxide Layer					
Thickness*	0.02 ~ 5.0				μ m
Handle Layer					
Thickness*	200 ~ 1250	500 ~ 750			μ m
Surface	Lapped / Etched / Polished				
* Other customized specifications are welcome					



Sapphire Wafer

Product Name	Sapphire Wafer			Unit
Diameter	50.8	100	150	mm
Thickness*	430± 15	650± 15	1300± 25	μm
Surface Orientation*	C-Plane (0001) tilted M-axis 0.2°± 0.1°			degree
Primary Flat	A-Axis (11-20) ± 0.2°			degree
Orientation Length	16 ± 0.5	30 ± 1.0	49.0 ± 1..0	mm
TTV	≤ 5	≤ 10	≤ 15	μm
Bow	0~-10	0~-10	0~-20	μm
Warp	≤ 10	≤ 15	≤ 30	μm
Roughness Front Side	≤ 0.2	≤ 0.2	≤ 0.2	nm
Roughness Back Side	0.8 ≤ Ra ≤ 1.2			μm
Wafer Edge*	R-Type / T-Type			
Laser Mark*	On Front Side Near Primary Flat			
* Other surface conditions & customized specifications are welcome				



GaAs Wafer

Product Name	GaAs Wafer			Unit
Diameter	50.8 ~ 150			mm
Dopant	N / Si	P / Zn	SI / Carbon	
Thickness*	(350 ~ 675) ± 25			µm
Surface Orientation*	On-axis : (100) ± 0.5° Off-axis: 2° / 6° / 15° off toward <111> ± 0.5°			degree
Hall Mobility*	≥1000 ~ 2500	≥50 ~ 120	≥4000~5000	cm ² /V.S
Etch Pit Density*	≤100 ~ 5000	≤ 3000 ~ 5000	≤ 1500 ~ 5000	cm ⁻²
Carrier Concentration*	(0.8 ~ 4.0) x 10 ¹⁸	(0.5 ~ 5.0) x 10 ¹⁹	≤ 1 x 10 ⁸	cm ⁻³
TTV(DSP)*	≤ 4			µm
TTV(SSP)*	≤ 10			µm
Warp*	≤ 15			µm
Front Side	Etched or Polished			
Back Side	Etched or Polished			
* Other surface conditions & customized specifications are welcome				

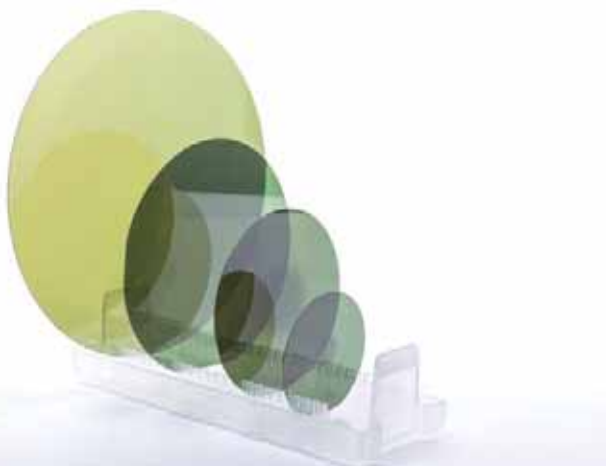


GaAs Epitaxial Wafer

Product Name	GaAs Epitaxial Wafer (LD)				Unit
Application	Laser Diodes				
Wavelength	680 ~ 850	739~808	640~690	980~1080	nm
Epitaxial Structure	$\text{Al}_{(x)}\text{Ga}_{(1-x)}\text{As}/\text{GaAs}$	GaAsP/GaAs	AlGaInP/InGaP/GaAS	InGaAs/AlGaAs/GaAs	
Thickness Uniformity	± 1.5				%
Carrier Conc. Uniformity	± 10				%
N-doping Limit	$\leq 5 \times 10^{18}$				cm^{-3}
P-doping Limit	$\geq 7 \times 10^{19}$				cm^{-3}
Carrier Mobility at $N=2 \times 10^{17}$	≥ 3000				$\text{cm}^2/\text{V.S}$
Composition Uniformity	$x = 0.497 \sim 0.503$				
Substrate Diameter	2" ~ 4"				
* Other customized specifications are welcome					

SiC Wafer

Product Name	SiC Wafer				Unit
Diameter	50.8	76.2	100	150	mm
Type	4H- N / 4H-SI / 6H-N / 6H-SI				
Resistivity	4H-N: 0.015 ~ 0.028 ; 4H/6H-SI: >1E5 ; 6H-N: 0.02 ~ 0.1				Ω.cm
Thickness*	(330 ~ 500) ± 25				μm
Orientation*	On-axis: <0001> ± 0.5° Off-axis: 4° ± 0.5° off toward (11-20)				degree
Primary Flat*	(10-10) ± 5.0°				degree
Secondary Flat	Silicon Face: 90° CW from Primary ± 5.0°		None		degree
TTV*	≤15				μm
Bow*	≤25		≤40		μm
Warp*	≤25	≤35	≤40	≤60	μm
Micropipe Density	Zero: ≤1 / Production: ≤5 / Research: ≤15 / Dummy: ≤50				cm ⁻²
Roughness	Polished (Ra ≤ 1)				nm
	CMP (Ra ≤ 0.5)				
* Other customized specifications are welcome					



SiC Epitaxial Wafer

Product Name	SiC / SiC Wafer		Unit
Diameter	50.8 ~ 150		mm
Conductivity	N - Type	P -Type	
Dopant	Nitrogen	Aluminum	
Carrier Concentration	$9 \times 10^{14} \sim 1 \times 10^{19}$	$9 \times 10^{14} \sim 1 \times 10^{19}$	cm^{-3}
Tolerance	± 15	± 50	%
Uniformity	≤ 10	≤ 20	%
Thickness*	0.2 ~ 50		μm
Tolerance	± 10		%
Uniformity	≤ 10		%
Defects	< 1		cm^{-2}
Roughness (20 μm X20 μm)	≤ 0.5		nm
Scratches	$< 1 \times \text{wafer diameter}$		ea/mm
Usable Area	≥ 90		%
* Other customized specifications are welcome			

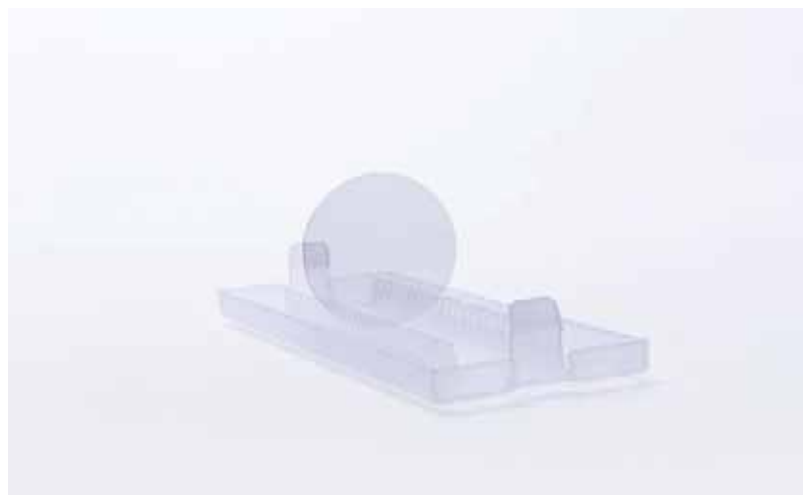
SiC Chip/Diode

Product Name	SiC Schottky Chip/Diode				Unit
V_R (Max)	650	1200	1700	3300	V
I_F (Max)	3 ~ 100	2 ~ 50	5 ~ 15	0.6 ~ 50	A
V_F (Max)	≤ 1.7 ~ 2.3				V
$T_{j(Max)}$	-55 ~ 175				°C
Package*	TO-220 / TO-247 / TO-252 / TO-263				
* Other customized specifications are welcome					



GaN Wafer – Free Standing

Product Name	GaN-FS			Unit
Dimension*	(5.0~10.0) x (10.0~20.0) ; ± 0.2			mm ²
	50.8 ± 1.0			mm
Type/Dopant	N / Ge	N / Undoped	SI / Fe	
Resistivity	< 0.05	< 0.5	>10 ⁶	Ω.cm
Orientation*	C-plane (0001) off toward M-Axis 0.35°± 0.15°			degree
Thickness*	350 ± 25			μm
Dislocation Density	(0.5~3) x 10 ⁶	(0.1~3) x 10 ⁶	(0.1~3) x 10 ⁶	cm ⁻²
TTV*	≤ 15			μm
Bow*	≤ 20			μm
Front Surface	Polished (Ra<0.2nm)			
Back Surface	Fine ground			
Useable Surface Area	> 90			%
* Other conditions & customized specifications are welcome				



GaN Wafer – Template

Product Name	GaN-Temp			Unit
Diameter	50.8 ± 0.1	100 ± 0.1		mm
Orientation	C-axis(0001) ± 0.5°			degree
Type	P-type (Mg-doped)	N-type (Si-doped)	N-type (Undoped)	
Resistivity	~10	< 0.5	< 0.05	Ω.cm
Thickness	4	4 or 20		μm
Carrier Concentration	> 6 X 10 ¹⁶	< 5 X 10 ¹⁷	> 1 X 10 ¹⁸	cm ⁻³
Mobility	~10	~300	~200	cm ² /V.s
Dislocation Density	< 5 X 10 ⁸			cm ⁻²
Substrate Structure	GaN on Sapphire (0001) (SSP or DSP)			
Useable Surface Area	> 90			%

GaN Epitaxial Wafer

Product Name	GaN EPI Wafers				Unit
Substrate	Silicon	HR Silicon	SiC	Sapphire	
Diameter	50.8 ~ 200	150 ~ 200	50.8 ~100		mm
Epi-layer thickness	>3	~2	0.5~3		μm
Crystalline AlGaN/GaN HEMT	<800" (002) & <2000" (102)	<700" (002) & <1350" (102)	<250" (2μm GaN)	<400" (2um GaN)	-
Composition AlGaN/GaN HEMT	$Al_xGa_{1-x}N$ ($0 < x < 0.5$)				
AlGaN barrier thickness	2~50				nm
AlN spacer*	0.2-2				nm
Surface morphology (5x5μm ²)	RMS<0.5				nm
Bow	<50				μm
2DEG	>9E12(25nm Al _{0.25} GaN)		>8E12 (25nm Al _{0.25} GaN)		/cm ²
Electron mobility (cm ² /Vs)	>1500	>1800	>2000	>1500	cm ² /Vs
Sheet resistance	<400(25nm Al _{0.25} GaN)				Ω.cm
Buffer resistivity	>10 ⁵				Ω.cm
* Other customized specifications are welcome					

GaN Chip/Diode

Product Name	GaN Chip/Diode				Unit
Parameter	FET		SBD		
$V_{R(Max)}$	200	600	200	600	V
$I_{F(Max)}$	20	10	20	10	A
$I_{R(Max)}$	≤ 0.1		≤ 1.0		μA
$R_{DS(on)}$	0.05	0.15	-		Ω
$V_{F(Max)}$	-		≤ 1.5		V
$T_{j(Max)}$	-55 ~175				$^{\circ}C$
* Other customized specifications are welcome					



AlN Wafer

Product Name	AlN Wafer	Unit
Diameter	50.8 ± 0.1	mm
Type	Semi-Insulating	
Thickness	4~5	μm
Orientation	C-axis(0001) ± 1.0°	degree
Crystalline	XRD FWHM of (0002) < 350	arcsec
	XRD FWHM of (10-12) < 450 arcsec	
Edge Exclusion	< 2	mm
Surface Roughness (10 μm x 10 μm)	Ra < 5	nm
Substrate	Sapphire (Single side polished)	

InP Wafer

Product Name	InP Wafer			Unit
Diameter	50.8 ~ 100			mm
Orientation*	(100) ± 0.5°			degree
Thickness*	(350~625) ± 25			μm
Type/Dopant	N / S or Sn	P / Zn	N / Undoped	
Carrier Concentration	(0.8-8) × 10 ¹⁸		(1-10) × 10 ¹⁵	cm ⁻³
Mobility	(1-2.5) × 10 ³	50 ~ 100	(3-5) × 10 ³	cm ² /Vs
Etch Pitch Density	100 ~ 5000	≤ 500	≤ 5000	cm ²
TTV*	SSP : ≤ 15 DSP : ≤ 10			μm
Warp	≤ 15			μm
Surface	Etched or Polished			
* Other customized specifications are welcome				



Germanium Wafer

Product Name	Germanium Wafer		Unit
Diameter	50.8 ~ 150		mm
Dopant	P / Ga	N / As	
Resistivity	0.005 ~ 0.04	0.05 ~ 0.25	$\Omega \cdot \text{cm}$
Orientation*	(100) \pm 0.5		degree
Thickness*	175 \pm 25		μm
Etch Pit Density	\leq 300		cm^{-2}
TTV	\leq 10		μm
Warp	\leq 15		μm
Front Side Surface	Etched or Polished		
Back Side Surface	Etched or Polished		
Edge Profile	Round		
* Other customized specifications are welcome			

LN / LT Wafer

Product Name	Lithium Niobate LiNbO_3 (LN) Wafer Lithium Tantalate LiTaO_3 (LT) Wafer			Unit
Diameter	76.2	100	150	mm
Orientation	LN: 64° Rot. Y-cut $\pm 0.2^\circ$ / 127.86° Rot. Y-cut $\pm 0.2^\circ$ / Y-cut $\pm 0.2^\circ$ LT: 36° Rot. Y-cut $\pm 0.2^\circ$ / 42° Rot. Y-cut $\pm 0.2^\circ$ / X-cut $\pm 0.2^\circ$			degree
Primary Flat	LN: Perpendicular to X $\pm 0.2^\circ$ / Perpendicular to Z $\pm 0.2^\circ$ LT: Perpendicular to X $\pm 0.2^\circ$ / Perpendicular to 112.2° Y $\pm 0.2^\circ$			degree
Secondary Flat	LN: CW 180° / CW 225° / CW $270^\circ \pm 0.5^\circ$ from Primary LT: CW 225° / CW 270° / CW $315^\circ \pm 0.5^\circ$ from Primary			degree
Thickness*	$(200 \sim 500) \pm 20$			μm
TTV	≤ 10			μm
Bow	≤ 25			μm
Front Surface	$R_a \leq 8$			\AA
Back Surface	LN: $0.2 \leq R_a \leq 0.7$ LT: $0.2 \leq R_a \leq 0.5$ or $0.08 \leq R_a \leq 0.15$			μm
Edge Beveling	Rounded			
Curie Temp.	LN: 1142 ± 3 LT: 605 ± 3			$^\circ\text{C}$
* Other surface conditions & customized specifications are welcome				

LED Wafer – AlGaInP Wafer/Chip

Product Name	AlGaInP LED Wafer / Chip				Unit
Color	Red: 615 ~ 645nm Yellow: 580 ~ 597nm Orange: 595 ~ 617nm			Yellow-Green: 565~575nm	
Size	6.5 ~ 12	8 ~ 14	24 ~ 40	6.5 ~ 12	mil
Polarity	Positive pole	Anti-pole	Anti-pole	Positive pole	
Brightness	10 ~ 300	175 ~ 700	2800 ~ 15000	10 ~ 120	mcd
Voltage	≤ 2.2	≤ 2.3	≤ 3.0	≤ 2.2	V
* Other customized specifications are welcome					



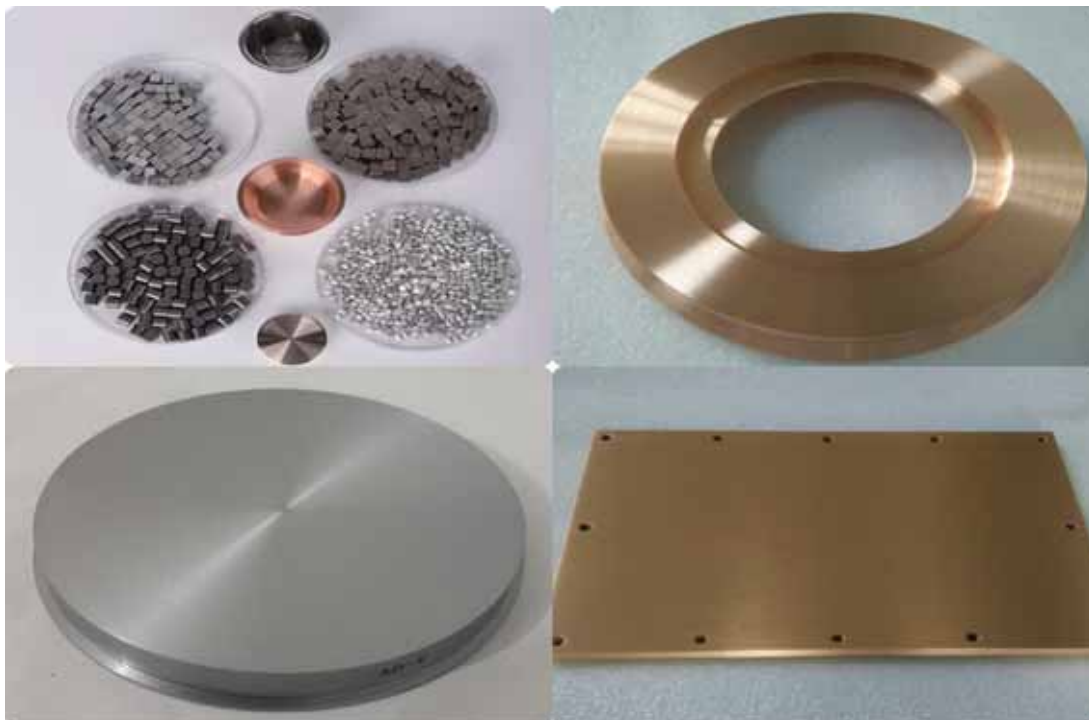
LED Wafer – GaN Wafer/Chip

Product Name	GaN LED Wafer / Chip			Unit
Color	Blue (For white light)	Blue	Green	
Wavelength	445 ~ 460	460 ~ 470	505 ~ 535	nm
Size*	8 ~ 40			mil
Brightness	52 ~ 72	3.7 ~ 5.9	3.5 ~ 5.5	mW
Voltage	≤ 3.0 ~ 3.5	≤ 2.8 ~ 3.2	≤ 2.8 ~ 3.1	V
* Other customized specifications are welcome				



Target – Deposition Materials

Deposition Materials	
Sputtering Targets	Pure Metal / Alloy / Oxide / Nitride / Sulfide / Fluoride / Carbide
Pure Metal	Al, Ti, Cr, Co, Cu, Zr, Zn, Sn, Mo, Ag, Au...
Alloy	TiAl, TiCu, TiSi, TiCr AlSi, NiCr, NiTi, NiV, NiFe...
Compound	ZnO, TiO ₂ , ITO, AlN, BN, CdS, MgF ₂ ...
Evaporation Materials	Pure Metal / Compound
Pure Metal	Ti, Ni, Ag, Al, Cu
Compound	ZrO ₂ , Ta ₂ O ₅ , Ga ₂ O ₃ , HfO ₂ , Nb ₂ O ₅ ...
PVD - Supplies	Crucible / Boat / Wire / Crystal
Crucible	W Crucible, Mo Crucible, Ta Crucible...
Boat	W Boat, Mo Boat, BN Boat...
Wire / Crystal	W Basket, Al Wire, Crystal
* Other customized Target materials are welcome	



Powder – Al_2O_3 & SiO_2

- **Boehmite Alumina Powder**

- Formula: $\gamma\text{-AlO}(\text{OH})$
- Purity: up to 99.995%

- **Alumina Powder**

- Formula: $\alpha\text{-Al}_2\text{O}_3$ and $\gamma\text{-Al}_2\text{O}_3$
- Purity: up to 99.995%

- **SiO_2 Powder**

- Purity: up to 99.995%



Multi Solar Wafer

Product Name	Multi Solar Wafer		Unit
Parameter	M0	M2	
Diameter	156 x 156 ± 0.5	156.75 x 156.75 ± 0.5	mm ²
Diagonal	219.2±0.5	220±0.5	mm
Chamfering	0.5 ~ 1		mm
Square	90°±0.3°		degree
Type / Dopant	P / Boron		A
Resistivity	1 ~ 3		Ω.cm
Thickness	200±20		μm
Oxygen Concentration	≤ 10 x 10 ¹⁷		at/cm ³
Carbon Concentration	≤ 7x 10 ¹⁷		at/cm ³
Lifetime	≥ 2		μs
TTV	≤ 30		μm
Warp	≤ 40		μm
Saw Mark	≤ 15		μm
Surface	As cut and cleaned		

* Other customized specifications are welcome



Mono Solar Wafer

Product Name	Monocrystalline Silicon Solar Wafer					Unit
Parameter	M1	M2	M4	Thin Wafer	Square Wafer	
Diameter	205	210	211	160/205/210/211	219/220	mm
Flat Length	156*156	156.75*156.75	161.70*161.70	125 ~ 162	156 ~ 156.75	mm ²
Orientation	<100> ; <110>					degree
Resistivity	P-Type: 0.3 ~ 3.0 N-Type: 0.1 ~ 20					Ω.cm
Thickness	170 ~ 200	170 ~ 200	170 ~ 200	90 ~ 130	130 ~ 180	μm
Surface	As Cut & Cleaned					
* Other customized specifications are welcome						



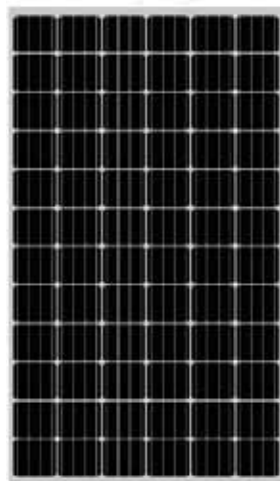
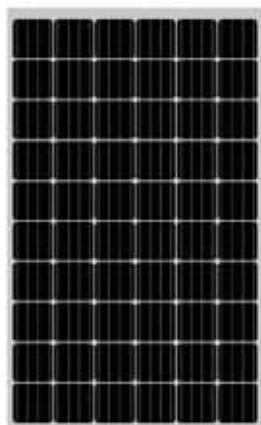
Mono PERC Solar Cell

Product Name	Monocrystalline PERC Solar Cell					Unit
Parameter	M2 - 4BB			M2 - 6BB	M4 - 5BB	
Dimension	156.75*156.75 ~ 210			156.75*156.75 ~ 210	161.8*161.8 ~ 211	mm ²
Efficiency	21.0	21.1	21.2	21.3	21.3	%
Power	5.13	5.15	5.18	5.2	5.51	W
Voc	0.661	0.662	0.663	0.664	0.663	V
Imp	9.663	9.670	9.702	9.690	10.298	A
Fill Factor	80.32%	80.45%	80.53%	80.82%	80.70%	%
Thickness	160 ~ 200					μm
* Other customized specifications are welcome						



Solar Modules

Product Name	Solar Modules								
Cell Type	Number of Cells	Dimension (mm ³)	Pmax (W)	Tolerance (W)	Vmpp (V)	Imp (A)	Voc (V)	Isc (A)	Efficiency (%)
Mono	60	1650x992x40	265	0-+5	30.50	8.69	38.2	9.15	>16.30
	60	1650x992x40	270	0-+5	30.80	8.78	38.4	9.27	>16.60
	60	1650x992x40	275	0-+5	30.90	8.91	38.5	9.36	>16.90
	60	1650x992x40	280	0-+5	31.00	9.02	38.7	9.47	>17.20
	60	1650x992x40	285	0-+5	31.20	9.13	38.8	9.56	>17.50
	72	1965x992x46	325	0-+5	37.20	8.73	46.1	9.25	>16.90
	72	1965x992x46	330	0-+5	37.60	8.78	46.3	9.29	>17.10
	72	1965x992x46	335	0-+5	37.90	8.83	46.7	9.32	>17.4
Poly	60	1650x992x40	250	0-+5	30.00	8.34	37.40	8.88	>15.30
	60	1650x992x40	255	0-+5	30.30	8.42	37.60	8.96	>15.60
	60	1650x992x40	260	0-+5	30.60	8.50	37.80	9.04	>15.90
	60	1650x992x40	265	0-+5	30.90	8.58	38.00	9.12	>16.20
	60	1650x992x40	270	0-+5	31.20	8.66	38.20	9.20	>16.50
	72	1956x992x46	300	0-+5	35.80	8.40	44.50	8.95	>15.50
	72	1956x992x46	305	0-+5	36.10	8.45	44.80	9.00	>15.70
	72	1956x992x46	310	0-+5	36.50	8.50	45.10	9.05	>16.00
	72	1956x992x46	315	0-+5	36.90	8.55	45.40	9.10	>16.30
	72	1956x992x46	320	0-+5	37.30	8.60	45.70	9.15	>16.50

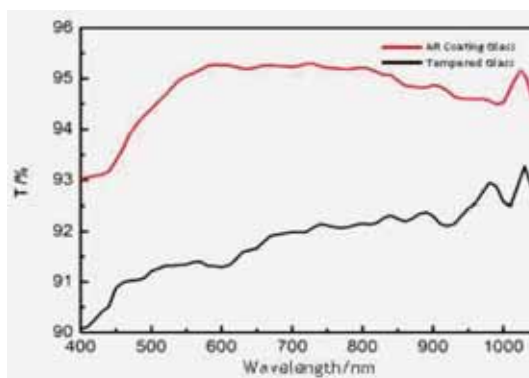


Solar Glass

Product Name	Solar Glass			Unit
Dimension(Max)	1950×2500 (Raw Plate)/ 1150×2500 (Tempered)			mm ²
Regular Dimension	1643×985 / 1634×984 / 1574×805 / 1634×986			mm ²
Optical Property				
Thickness	2.5	3.2	4.0	mm
Reflectance	7.6			%
Sun Light Transmitted	>91.6			%
Coated Transmitted	94.5			%
Mph's Scale (Scratch Harness)	5			
Knoop Harness Number Indenter Load-500g	470			
Poisson's Ratio	0.217			
Density	2.4872			g/cm ³
(Young's) Modulus of Elasticity	70.000			N/mm ²
Tensile Strength	25			N/mm ²
Specific Gravity	700-900			N/mm ²
Mechanical Strength	90			N/mm ²
Thermal Property				
Specific Heat	0.2			J/Kg.K
Calculated Thermal Conductivity at 20°C	1.0W			W/mK
Softening Point	743.3			°C
Annealing Point	577			°C
Strain Point	537.4			°C
Expansion Co-Efficiency Linear In the Range of 20°C-300°C	8.64×10 ⁻⁶			

Transmittance Curve Comparison

Diagram



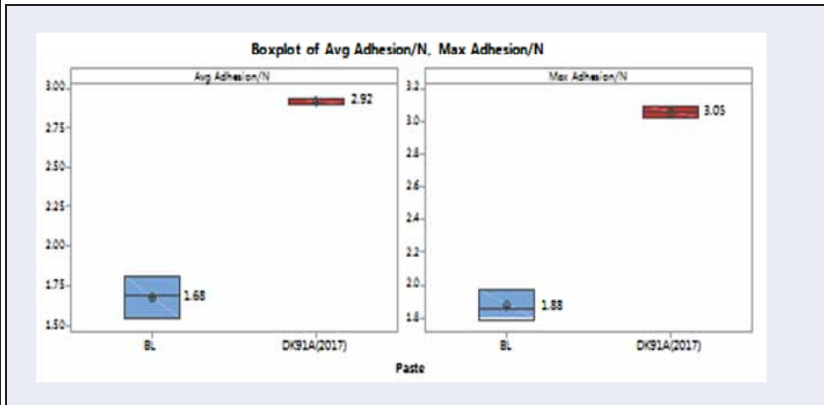
Junction Box

Product Name	Junction Box
Rated Voltage	1500V DC
Rated Current	15A
Rated Impluse Voltage	16000V
Ambient Temperature	-40°C~+85°C
Degree of protection	IP67
Contact Resistance	<13.0mΩ(1m) Accroding to the customer cable length is confirmed
Polarity of the connector	Socket=Plus/Positive Plug=Minus / Negative
Type of Termination	Welding
Contact Material	Copper, Ni-Plated
Insulation Material	PP0 V0150B
Flame Class	UL94-V0
TUV Rheinland	R50361173
Cable specification	4mm ²
Warning	Do not disconnect under load



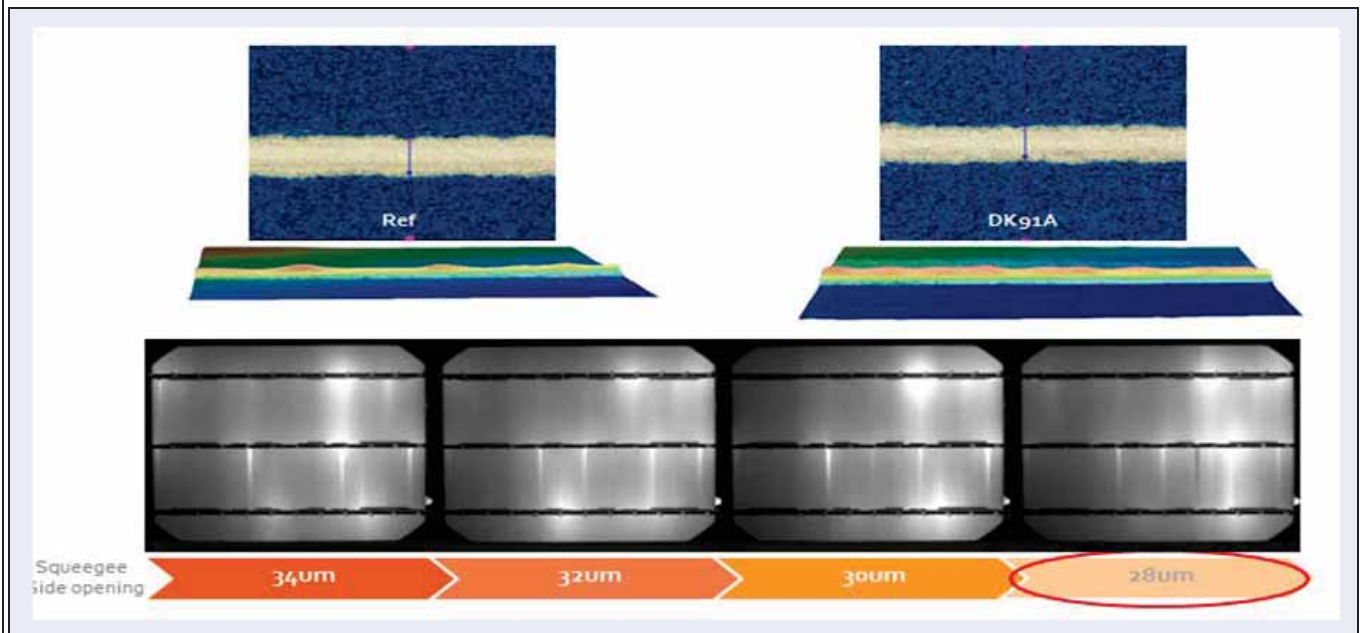
Silver Paste for DWS Multi(incl. Black Silicon)

DK91A							
Mass production data of DK91A on std multi							
Paste	Uoc (mV)	Isc (A)	Rs (mOhm)	Rsh (Ohm)	FF (%)	Eff (%)	Qty(Pcs)
Ref	632.4	9.045	1.64	240	80.47	18.92%	1039
DK91A	632.6	9.064	1.71	241	80.59	18.99%	1128
Ref	635.1	9.087	1.57	191	80.08	19.00%	398
DK91A	635.4	9.109	1.5	160	80.26	19.08%	397
Ref	635.5	9.146	1.72	140	80.01	18.93%	4578
DK91A	636.0	9.160	1.54	132	80.35	19.04%	5895



1. Adhesion improved >1 N
2. Meet the strict requirement of DWS and 5BB

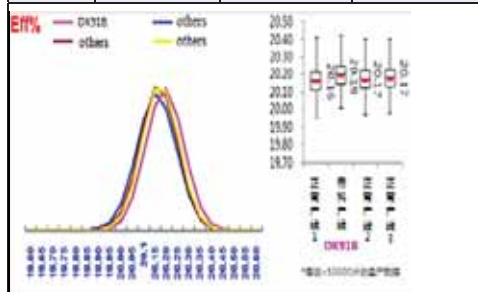
Compatible with standard multi



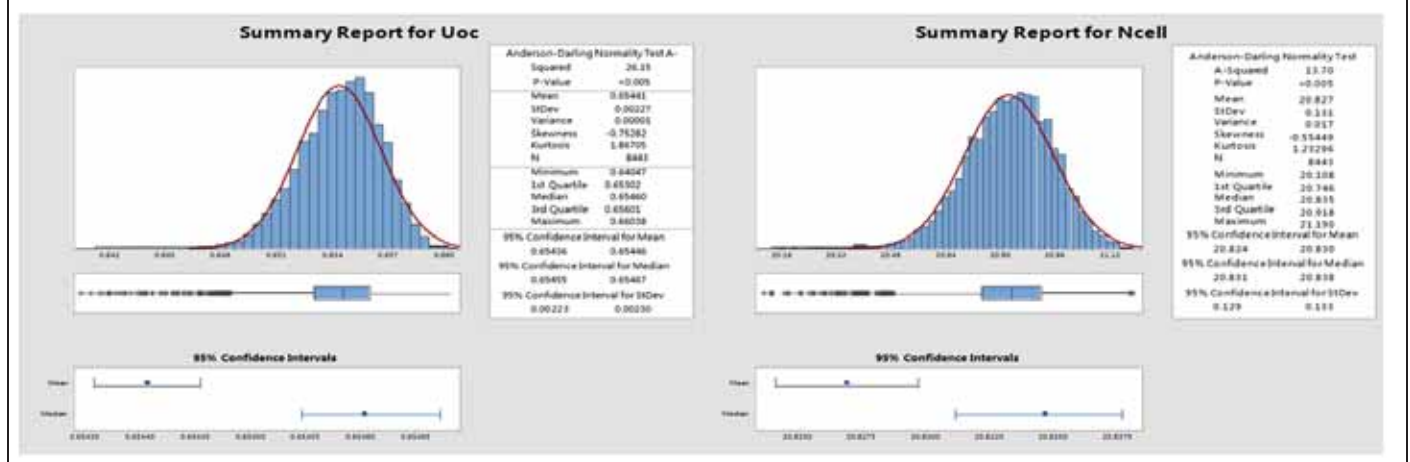
Silver Paste for Mono PERC(incl. Standard Mono)

DK91B						
Mass production data of DK91B on standard mono						
Paste	Uoc(mV)	Isc (A)	Rs (mOhm)	Rsh (Ohm)	FF (%)	Eff (%)
Ref	646.8	9.308	1.01	1637.0	81.28	20.03%
DK91B	647.0	9.323	0.99	1631.0	81.34	20.08%
Ref	646.3	9.302	0.98	1645.0	81.27	20.00%
DK91B	647.0	9.320	0.99	1538.0	81.30	20.06%

Mass production data of DK91B on PERC mono compared to D/H PERC pastes								
Paste	Peak-T	Uoc (mV)	Isc (A)	Rs (mOhm)	Rsh (Ohm)	FF (%)	Eff (%)	Qty(Pcs)
Ref	BSL	662.8	9.694	2.59	2362	79.52	20.90	1377
DK91B	BSL-15°C	663.1	9.721	2.54	5618	79.61	21.00	1489
Ref	BSL	659.0	9.808	2.88	786	79.18	20.95	426
DK91B	BSL-10°C	660.4	9.830	2.75	1844	79.20	21.04	490
Ref	BSL	662.1	9.644	2.03	610	79.48	20.8	14774
DK91B	BSL-8°C	662.8	9.676	2.01	636	79.49	20.9	10040

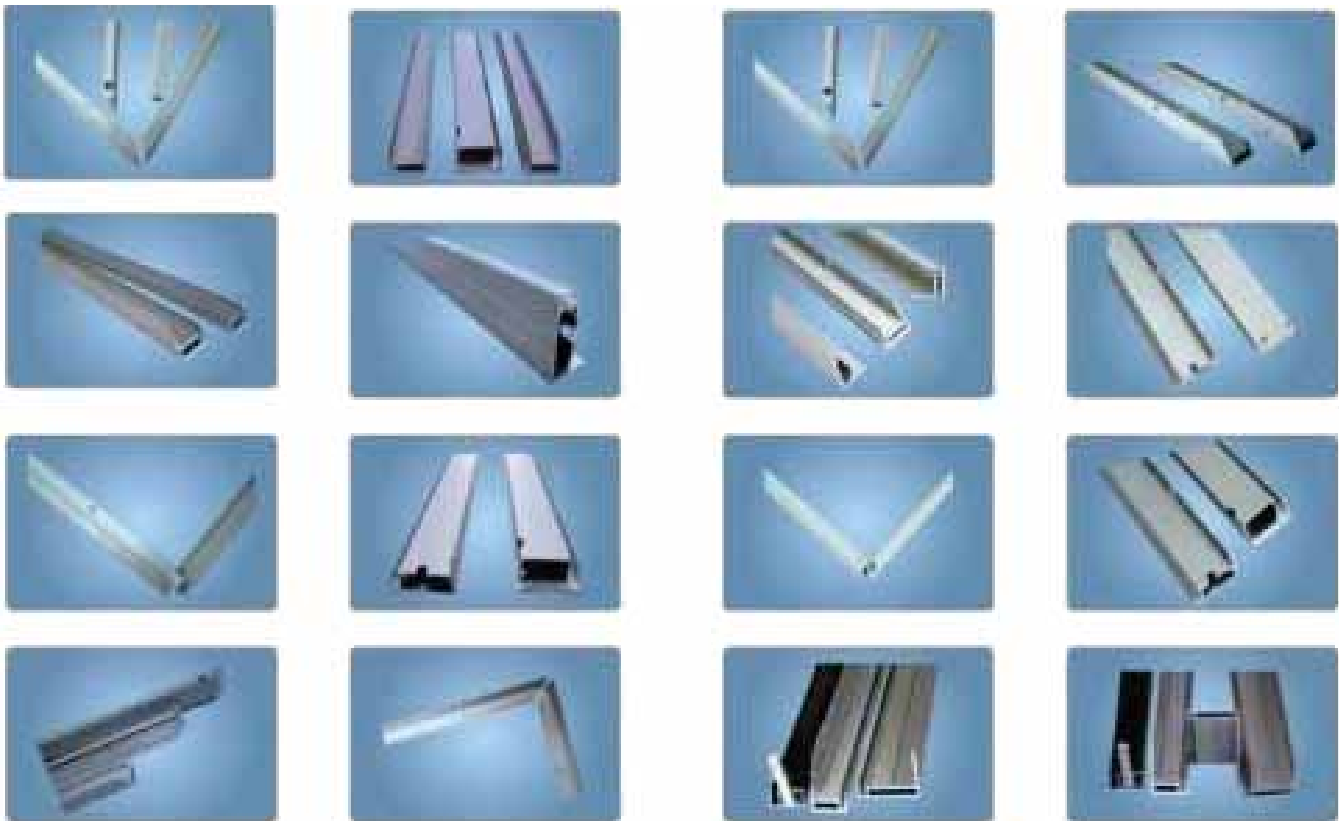


1. DK91B compatible data with standard Mono
 2. ATECOM is the only 4 suppliers of silver pastes for advanced mono cells with high quality and process window



Aluminum Solar Panel

Product Name	Aluminum Solar Panel Frame
Material	Alloy 6063, 6061, 6005, 6060 Custom made available.
Temper	T3, T4, T5, T6,T66
Color	Natural color, Silver, Golden, Bronze, Black
Angle	45 or 90 degrees
Surface Treatment	Anodization(Clear, Satin, Bronze, Black, Golden, Silver, Other multicolor), Electrophoresis, Powder coating, PVDF coating, Wood grain painting
Mould size	25*25mm, 35*35mm,30*46mm,46*50mm, 30*25mm, 40*40mm ,50*35mm.
* Other customized Target materials are welcome	



Atecom Technology

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